

**SYSTEM FOR TESTING DEVICES AND METHOD THEREOF****ABSTRACT OF THE DISCLOSURE**

Systems and methods are provided for testing a device. A test fixture is provided for interfacing a device with a host system for generating tests to be run on the device. The device is placed in a scan-test mode, according to a built-in self-test of the device. A scan clock signal and scan pattern are provided to allow scan-tests to be run on the device. If the device passes the scan test, the device is placed in a real-time test mode. At-speed tests may then be run on the device to provide a robust test and identify portions of the device that may be faulty.